

Alpha Spectrometry Management Software



The Comprehensive Alpha Spectrometry Solution for Compatible, Efficient, and Defendable Alpha Measurements."



AlphaVision is a comprehensive PC-based alpha spectrometry application that combines rich features and intuitive processes to meet the demands of modern Radiochemistry Laboratories.

In large scale commercial laboratories with hundreds of alpha detectors or small labs with only a few detectors, AlphaVision is your solution to optimize routine measurement processes and monitor system performance.



#### Why AlphaVision?

Compatibility	<ul> <li>Windows 10 64-bit Compatible.</li> <li>Microsoft Access Database with Data Management tools and LIMS integration capability.</li> <li>Crystal Reports integration for Rich Standard Reports and Custom Report capability.</li> <li>Extensive Analysis capability to accommodate a wide variety of Radiochemistry processes.</li> </ul>
Process Efficiency	<ul> <li>Batch Configuration process with LIMS<sup>1</sup> integration to maximize throughput and minimize errors.</li> <li>Intuitive Sample Management including Query tools to quickly locate Batches and Samples.</li> <li>Rapid Data Review and Analysis modification process.</li> <li>Integrated Hardware control for up to 256 detectors in a common interface.</li> </ul>
Defendable Results	<ul> <li>Security controls to limit user access to authorized functions.</li> <li>Compliance with Industry Standards such as ANSI N13.30 and N42.23.</li> <li>Comprehensive Quality Control features.</li> <li>Historical Analysis retention when re-analyzing samples.</li> <li>Detailed Event Logging for routine operations, warnings, and errors.</li> </ul>

**Introducing AlphaVision 7.0!** 

**New!** 64-Bit Windows 10 Compatibility.

New! Alpha Mega now supported in the Instrument Group Control.<sup>2</sup>

**New!** Automatic Spectrum Export on Completion of Calibration Measurements.

**New!** Simple Spectrum Export from any spectrum window.

New! Notification of Communication Interruption on the Instrument Group Control.<sup>2</sup>

<sup>1</sup> Laboratory Information Management System.

<sup>2</sup> Hardware control is available for instruments with software control capability.







QA/QC

AlphaVision	Hardware Control
	α Rapid Detector "Group" Operations
Calibration	α Integrated Instrument Control Based on Instrument Type
i i i i	α Detector Status Indicators "at a glance"
Batch	α Automated Instrument Setup
Hardware	α Configurable Detector Grid
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#### Quality Assurance α ANSI N42.23 and ANSI N13.30 Compliant

- α Automated Control Charts and Reports
- α Warning/Alarm Limit Calculations
- α Monitoring Parameters:
  - √ Detector Background (Total and Isotopic)
  - $\sqrt{}$  Calibration Energy and Efficiency
  - $\sqrt{\text{Pulser Centroid and Width}}$
  - $\sqrt{\rm Detector}$  Bias and Chamber Pressure
  - $\sqrt{\text{Reagent Blank Nuclide Activity}}$
  - $\sqrt{\text{Control Sample Nuclide Activity}}$
  - $\sqrt{\text{Tracer Peak Width}}$
  - $\sqrt{\text{Chemical Recovery}}$





#### **Specifications**

Operating System Requirements	Windows 10 64-bit.
Supported Hardware	ORTEC Alpha Suite integrated spectrometers (Alpha Aria, Duo, Ensemble, and Mega) are recommended in order to take advantage of the software controlled operations and Windows 10 64-bit USB connectivity.
	Legacy instrumentation compatible with ORTEC CONNECTIONS such as ORTEC OCTÊTE-PC, OCTÊTEPlus, 576A, Soloist, 920 series, and Oxford OASIS, as well as the ORTEC 676 Alpha King, Tennelec TC-256, and Canberra 7401/7404 models which are supported through ORTEC MCBs may be available through networked connection to computers running compatible Operating Systems or using the DPM-USB for native Windows 10 compatibility if supported. Contact your local ORTEC representative for questions related to legacy instrument compatibility.
Analysis Methodology	<ul> <li>Peak Search/Fit Methods: Second Derivative (Mariscotti)<sup>3</sup>, Top Hat Correlation<sup>4</sup>, Peak Interference Correction, ROI (Regions of Interest) including automatic shift of ROIs based on the Tracer Peak, Best Peak, or All Peak positions, and Interactive ROI Adjustment to optimize peak fit during reanalysis.</li> <li>Nuclide Activity Calculations: Absolute (no Tracer), Tracer Recovery Correction, Chemical Recovery Correction (Automatic and Manual), Background Subtraction, Blank Subtraction, Total Propagated Uncertainty.</li> <li>MDA Methods: KTA, Currie, ANSI N13.30, (corrections such as dilution scaling, tracer and chemical recovery, etc. included).</li> <li>Presets: Real and Live Time, Tracer Peak Area, MDA.</li> </ul>
System Management	<ul> <li>Select, Archive, and Compact Database.</li> <li>Search Samples by Batch/Sample ID or Batch Tree Navigation.</li> <li>Event Log captures process information, warnings, and errors.</li> <li>Purge Data.</li> <li>Security: <ul> <li>Configuration – Save Batch Template, Edit Sample Properties and Client Info, Edit Master Nuclide Library, Nuclide Libraries, Standards, Tracers, and ROIs.</li> <li>Detector Management – Add, Remove, Configure, Move, Edit Properties, Calibrate, Edit Chamber Pressure and Leakage Current Thresholds.</li> <li>Quality Assurance – Edit QA Types and Limits.</li> <li>System – View and Clear Event Log, Edit Batch Tree, Edit Users and Security Levels.</li> </ul> </li> </ul>

#### **Ordering Information**

Description
AlphaVision Alpha Spectrometry Management Software for Windows. Includes standalone or first network copy and binary use license.
AlphaVision software (A36-BW) with V&V Test Results and Certificate of Validation (A36-VW).
Single Use Network Copy. Requires current version of AlphaVision. Example: For a three-station network, order one copy of A36-BW and two copies of A36-NW.
Update from A36-B32, A36-BW, or A36-NW to latest version of AlphaVision.
AlphaVision software update (A36-UW) with V&V Test Results and Certificate of Validation (A36-VW).
Additional Hard Copy Documentation for AlphaVision.
AlphaVision V&V Test Results and Certificate of Validation.

<sup>3</sup>M.A. Mariscotti. "A Method for Automatic Identification of Peaks in the Presence of Background and its Application to Spectrum Analysis," Nuclear Instruments and Methods 50, 309–320 (1967).

<sup>4</sup>K. Debertin and R.G. Helmer. Gamma- and X-Ray Spectrometry with Semiconductor Detectors, Elsevier Science, 1988. (If peak shapes are well-controlled (through good sample preparation) the Top-Hat method is likely to yield better results than the Mariscotti method in which peak width is a free parameter.)



#### www.ortec-online.com

Specifications subject to change 073021

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